A	O XIBANEO	SHEET 1 OF 1		
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m	BY APPLICANT	APPLICANT Bilyalov, et al.		
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FOREIGN PATENT DOCUMENTS								
EXAMINER	DOCUMENT NUMBER		DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
INITIAL				·			YES	МО
TT	1	JP03-235371	1/14/92	Japan (abstract only)				×
TT	2	JP05-283723	2/3/94	Japah (abstract only)				х

EXAMINER INITIAL	OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)				
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